



Institut
Ruđer
Bošković



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Characterization with a β -source setup of the FBK UFSD 3.2 & HPK2 LGAD productions

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In this contribution, I will present the characterization of the latest LGAD productions manufactured at FBK (UFSD3.2) and HPK (HPK2), performed with the β -source (Sr90) setup of the Torino Silicon Lab (INFN – University of Torino). In particular, I will focus on temporal resolution and gain measurements of either irradiated (up to a fluence of $2.5E15$ neq/cm²) and non-irradiated devices. Results on sensors with different gain layer depths and carbon implantation doses will be shown.

In addition, I will compare the performances of FBK UFSD3.2 sensors with four different active thicknesses (25, 35, 45, 55 μ m).

I will also discuss the issues faced during the development of a dry and cold (-30°C) setup and provide some informations on the Torino β -setup, both on the hardware and software side.

Primary author: SIVIERO, Federico (Universita e INFN Torino (IT))

Co-authors: ARCIDIACONO, Roberta (Universita e INFN Torino (IT)); CARTIGLIA, Nicolo (INFN Torino (IT)); COSTA, marco (University of Torino); SOLA, Valentina (Universita e INFN Torino (IT)); FERRERO, Marco (Universita e INFN Torino (IT)); TORNAGO, Marta (Universita e INFN Torino (IT)); MANDURRINO, Marco (INFN); MILANESIO, Matteo (Università Torino); BOSCARDIN, Maurizio (FBK Trento); CENTIS VIGNALI, Matteo (FBK); PATERNOSTER, Giovanni (Fondazione Bruno Kessler); DALLA BETTA, Gian-Franco (INFN and University of Trento); FICORELLA, Francesco (FBK); PANCHERI, Lucio (University of Trento); HAMMAD ALI, Omar (FBK); BORGHI, Giacomo (Fondazione Bruno Kessler)

Presenter: SIVIERO, Federico (Universita e INFN Torino (IT))

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